

**Automated identification of application-dependent safe faults in automotive systems-on-a-chips**  
**Bagbaba, Ahmet Cagri**; Augusto da Silva, Felipe; Sonza Reorda, Matteo; Hamdioui, Said; **Jenihhin, Maksim**; Sauer, Christian  
Electronics 2022 / art. 319 <https://doi.org/10.3390/electronics11030319> Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

### **Designing reliable cyber-physical systems**

Aleksandrowicz, Gadi; Arbel, Eli; Bloem, Roderick; **Devadze, Sergei**; **Jenihhin, Maksim**; Jutman, Artur; Raik, Jaan; **Shibin, Konstantin** Languages, design methods, and tools for electronic system design : selected contributions from FDL 2016 2018 / p. 15-38 : ill [https://doi.org/10.1007/978-3-319-62920-9\\_2](https://doi.org/10.1007/978-3-319-62920-9_2) Conference Proceedings at Scopus Article at Scopus

### **Health management for self-aware SoCs based on IEEE 1687 infrastructure**

**Shibin, Konstantin**; **Devadze, Sergei**; Jutman, Artur; Grabmann, Martin; Pricken, Robin IEEE Design & Test 2017 / p. 27-35 : ill <https://doi.org/10.1109/MDAT.2017.2750902>

### **Improved diagnostic approach for BRB detection and classification in inverter-driven induction motors employing sparse stacked autoencoder (SSAE) and lightGBM**

**Khan, Muhammad Amir**; **Asad, Bilal**; Vaimann, Toomas; **Kallaste, Ants** Electronics (Switzerland) 2024 / art. 1292 <https://doi.org/10.3390/electronics13071292>

### **On-line fault classification and handling in IEEE1687 based fault management system for complex SoCs**

**Shibin, Konstantin**; **Devadze, Sergei**; **Jutman, Artur** LATS 2016 : 17th IEEE Latin-American Test Symposium, Foz do Iguaçu, Brazil, 6th-9th April 2016 2016 / p. 69-74 : ill <https://doi.org/10.1109/LATW.2016.7483342>